## **LIST OF EXHIBITS**

## IPR2013-00363

ZEISS 1101	U.S. Patent No. 7,348,575 ("the Omura Patent")
ZEISS 1102	U.S. Patent No. 7,309,870 ("the Omura '870 Patent")
ZEISS 1103	Judgment, Paper No. 49, Interference No. 105, 678 ("the '678 Judgment")
ZEISS 1104	Judgment, Paper No. 157, Interference No. 105, 749 ("the '749 Judgment")
ZEISS 1105	Judgment, Paper No. 41, Interference No. 105, 753 ("the '753 Judgment")
ZEISS 1106	Judgment, Paper No. 291, Interference No. 105, 834 ("the '834 Judgment")
ZEISS 1107	Certified English Translation of Japanese Unexamined Patent Publication No. JP 2003-128154
ZEISS 1108	Certified English Translation of Japanese Unexamined Patent Publication JP 2003-350647
ZEISS 1109	Certified English Translation of Japanese Unexamined Patent Publication JP 2003-364596
ZEISS 1110	US Patent Application Publication No.US 2005/0036213 ("Mann")
ZEISS 1111	JP Patent Application Publication No. JP 2003-114387
ZEISS 1112	Certified English Translation of JP Patent Application Publication No. JP 2003-114387 ("Omura '387")
ZEISS 1113	PCT Patent Publication WO 02/035273 ("Takahashi PCT")
ZEISS 1114	European Patent Application Publication No. EP 1 336 887 A1 ("Takahashi")
ZEISS 1115	Satori Asai et al., "Resolution Limit for Optical Lithography Using Polarized Light Illumination," Jpn. J. Appl. Phys. Vol. 32, pp. 5863-5866 (1993) ("Asai")



ZEISS 1116 Expert Declaration of Richard C. Juergens  ZEISS 1117 Wikipedia, "Optical Power," https://en.wikipedia.org/wiki/Optical_power (downloaded May 20, 2013)  ZEISS 1118 Willi Ulrich et al., "The Development of Dioptric Projection Lenses for DUV Lithography," Proc. SPIE Vol. 4832, pp. 158-169 (2002) ("Ulrich")  ZEISS 1119 Eugene Hecht, Optics (4th ed.), Addison Wesley (2002), pp. 171-173.  ZEISS 1120 Wikipedia, "Optical Axis," https://en.wikipedia.org/wiki/Optical_axis (downloaded May 20, 2013)  ZEISS 1121 New World Dictionary of the American Language, Second College Edition, p. 1552, Simon and Schuster (1980)  ZEISS 1122 File History Excerpts from U.S. Serial No. 11/266,288 ("Omura Application")  ZEISS 1123 US Patent No. 5,825,043 ("Suwa")  ZEISS 1124 Wikipedia, "Refractive Index," http://en.wikipedia.org/wiki/Refractive_index (downloaded May 20, 2013)  ZEISS 1125 U.S. Patent No. 4,346,164 ("Tabarelli")  ZEISS 1126 File History Excerpts from U.S. Serial No. 11/513,160 ("Omura Continuation Application")  ZEISS 1127 J.R. Sheats and B.W. Smith, Microlithography: Science and Technology, Marcel Dekker, Inc. (1998), Chapter 1, pp. 1-43.  ZEISS 1128 Omura Reply 1, Paper No. 200, Interference No. 105,834  ZEISS 1130 CODE V Sequence Data  ZEISS 1131 CODE V Sub-routines  ZEISS 1132 OPTI 517 Lens Design Fall 2013		
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